Weak localization in electric-double-layer gated few-layer graphene

This content has been downloaded from IOPscience. Please scroll down to see the full text.

2017 2D Mater. 4 035006


View the table of contents for this issue, or go to the journal homepage for more

Download details:

IP Address: 129.169.173.133
This content was downloaded on 03/08/2017 at 14:54

Please note that terms and conditions apply.

You may also be interested in:

Enhanced intervalley scattering in artificially stacked double-layer graphene
M Z Iqbal, Özgür Kelekçi, M W Iqbal et al.

Disorder and electronic transport in graphene
E R Mucciolo and C H Lewenkopf

Localization and field-periodic conductance fluctuations in trilayer graphene
Mohammed S El-Bana, Daniel Wolverson, David W Horsell et al.

Localization and electron-electron interactions in few-layer epitaxial graphene
Shun-Tsung Lo, Fan-Hung Liu, Chang-Shun Hsu et al.

Recent experimental studies of electron dephasing in metal and semiconductor mesoscopic structures
J J Lin and J P Bird

Robust topological surface transport with weak localization bulk channels in polycrystalline Bi2Te3 films
H B Zhang, J D Yao, J M Shao et al.

Quantum corrections to transport in graphene: a trajectory-based semiclassical analysis
Martin Schneider and Piet W Brouwer

Raman characterization of defects and dopants in graphene
Ryan Beams, Luiz Gustavo Cançado and Lukas Novotny

The electronic properties of bilayer graphene
Edward McCann and Mikito Koshino
Weak localization in electric-double-layer gated few-layer graphene

R S Gonnelli, E Piatti, A Sola, M Tortello, F Dolcini, S Galasso, J R Nair, C Gerbaldi, E Cappelluti, M Bruna and A C Ferrari

1 Dipartimento di Scienza Applicata e Tecnologia, Politecnico di Torino, 10129 Torino, Italy
2 Istituto CNR-SPIN, Monte S. Angelo—via Cinthia, I-80126 Napoli, Italy
3 Istituto dei Sistemi Complessi del CNR, 00185 Roma, Italy
4 Cambridge Graphene Centre, University of Cambridge, Cambridge, CB3 OFA United Kingdom
5 Present address: Istituto Nazionale di Ricerca Metrologica (INRIM), 10135 Torino, Italy
E-mail: renato.gonnelli@polito.it

Abstract

We induce surface carrier densities up to \( \sim 7 \times 10^{14} \) cm\(^{-2} \) in few-layer graphene devices by electric double layer gating with a polymeric electrolyte. In 3-, 4- and 5-layer graphene below 20–30 K we observe a logarithmic upturn of resistance that we attribute to weak localization in the diffusive regime. By studying this effect as a function of carrier density and with \textit{ab initio} calculations we derive the dependence of transport, intervalley and phase coherence scattering lifetimes on total carrier density. We find that electron–electron scattering in the Nyquist regime is the main source of dephasing at temperatures lower than 30 K in the \( \sim 10^{13} \) cm\(^{-2} \) to \( \sim 7 \times 10^{14} \) cm\(^{-2} \) range of carrier densities. With the increase of gate voltage, transport elastic scattering is dominated by the competing effects due to the increase in both carrier density and charged scattering centers at the surface. We also tune our devices into a crossover regime between weak and strong localization, indicating that simultaneous tunability of both carrier and defect density at the surface of electric double layer gated materials is possible.

1. Introduction

Electrolytic gating, initially developed for polymeric transistors (see ref. [1] and references therein), is now used to study the transport properties of a wide range of materials, from semiconductors [2], to insulators [3] and superconductors [4–6]. This technique induces an orders-of-magnitude enhancement in the electric field at the sample surface, when compared to conventional solid gate techniques [7–10]. When a potential is applied between the sample and a counter electrode, the ions inside the polymeric (or liquid) electrolyte migrate and accumulate at the two surfaces, building up the so-called electric double layer (EDL) [7,8]. This acts as a nanoscale capacitor, and allows one to obtain surface variations of the carrier density, \( n_{\text{sl}} \), up to \( \sim 10^{14} - 10^{15} \) cm\(^{-2} \) [5], depending on the density of states of the sample and the electrochemical stability window of the electrolyte itself.

We firstly exploited an EDL to gate single layer graphene (SLG) in ref. [11] and bilayer graphene (BLG) in ref. [12]. Since then, this technique has been widely applied to study the transport properties of SLG [13–15] and few-layer graphene (FLG) [16–18]. Refs. [14, 15] studied the dominant scattering mechanisms in SLG for \( n_{\text{sl}} \) up to 6 and \( 1 \times 10^{13} \) cm\(^{-2} \), respectively. Ref. [15] reported a gate-tunable crossover of the resistivity from \( \rho \propto T \) to \( \rho \propto T^{4} \), in the range from 1.5 K up to room temperature (RT). This provides a clear example of Bloch–Grüneisen behavior in two dimensions (2D) due to a crossover from small-angle to large-angle electron–phonon (e–ph) scattering [19]. Ref. [16] reported an electric field-induced, gate-tunable band gap in rhombohedral stacked three-layer graphene (3LG) for \( n_{\text{sl}} \lesssim 1 \times 10^{13} \) cm\(^{-2} \). Ref. [17] showed that the \( n_{\text{sl}} \) achievable by electrolyte gating is large enough to populate the higher-energy bands in two layer (2LG) and three layer (3LG) graphene, away from the charge neutrality point. Ref. [18] demonstrated a gate-tunable crossover from weak localization (WL) to weak anti-localization (WAL) in the low-\( T \) transport properties of 3LG on SiC.

We reported \( n_{\text{sl}} \) up to \( \sim 3.5 - 4.5 \times 10^{13} \) cm\(^{-2} \) in thin films of Au and other noble metals with EDL gating by using a polymer electrolyte system (PES) of improved capacitance [21, 22] compared to previous experiments [7–10]. By using the same PES, we induced \( n_{\text{sl}} > 6 \times 10^{13} \) cm\(^{-2} \) in few-layer graphene (FLG)
mechanically exfoliated from highly oriented pyrolytic graphite (HOPG) [23]. One of the challenges at such high $n_{2d}$ is the observation of quantum phenomena, such as superconductivity. The induction of superconducting order in graphene would greatly benefit the development of novel device concepts [24], such as atomic-scale superconducting transistors [25], and superconductor-quantum dot devices [26, 27]. Superconductivity was reported in EDL-gated MoS$_2$ [6] and WS$_2$ [20]. Refs. [24, 28] theoretically predicted that this should also be the case for graphene. However, the experimental search for superconductivity in graphene via EDL-gating has so far been unsuccessful [15, 23], while low-\(T\) superconductivity has been demonstrated by alkali–metal decoration [29] and intercalation [30].

Here, we focus on the transport properties of EDL-gated 3LG, four (4LG) and five layer graphene (5LG) in the 4–30 K range. We find a small (\(\lesssim 1.5\%\)), gate tunable, upturn in the sheet resistance, $R_S$, below \(\sim 20–30\) K. This shows a logarithmic $T$ dependence, and its intensity is inversely correlated with $n_{2d}$. We demonstrate by magnetoresistance measurements that WL in the diffusive regime is at the origin of the upturn. This agrees well with the theoretical models developed for SLG and 2LG. Combining experiments with \textit{ab initio} calculations we extract the dependence of the characteristic scattering lifetimes with both $T$ and $n_{2d}$. From the dephasing lifetime dependence on $T$, we find that the dominant inelastic scattering mechanism for $T \lesssim 20$ K is electron–electron ($e-e$) scattering with small momentum transfer (Nyquist term) [35]. From its dependence on $n_{2d}$, we show that EDL gating brings the system in a crossover condition from WL to strong localization, and that this is gate-tunable in 5LG. Our results demonstrate quantum coherent transport in 4LG and 5LG for carrier densities in excess of $\sim 10^{13}–10^{14}$ cm$^{-2}$.

2. Fabrication and characterization

FLG flakes are prepared by micromechanical exfoliation of graphite on Si/SiO$_2$ [32, 33]. The number of layers, $N$, is determined by a combination of Raman spectroscopy [34, 35] and optical microscopy [31, 36]. EDL field-effect devices are then prepared by electron beam lithography and deposition of Cr/Au contacts in the Hall bar configuration, as shown in figure 1(b). A coplanar gate contact is deposited on the side. A protective poly(methyl methacrylate) (PMMA) layer is spin-coated, patterned and hard-baked on the completed devices in order to avoid interactions between the electrolyte and the metallic leads. A reactive mixture precursor of the PES is then drop-cast onto the whole device and UV-cured, to get a cross-linked photopolymer electrolyte [21, 23], figure 1(a). The precursor viscous liquid reactive mixture is composed of methacrylic oligomers and lithium salt: bisphenol A ethoxylate dimethacrylate (BEMA; average Mn: 1700, Aldrich), poly(ethylene glycol)methyl ether methacrylate (PEGMA; average Mn: 475, Aldrich), and 10% of lithium bis(trifluoromethanesulfonyl)
imide (LiTFSI) along with the addition of 3 wt% 2-hydroxy-2-methyl-1-phenyl-1-propanon as the free radical photoinitiator (Darocur 1173, Ciba Specialty Chemicals). No annealing is performed in the time between contact deposition and PES casting, and the devices are stored in a desiccator under low vacuum ($\sim 10^{-1} – 1$ mbar) to prevent contamination. We do not perform any annealing step before double-step chronocoulometry and transport measurements, because we are not interested in probing the properties of our samples close to the Dirac point. Thus, $n_{2d}$ near the charge neutrality point is larger compared to the typical values for exfoliated flakes ($\sim 10^{11} – 10^{12}$ cm$^{-2}$) [66, 67]. Four-wire resistance measurements are done under high vacuum ($< 10^{-5}$ mbar) in the chamber of a Cryomech pulse-tube cryocooler via a Keithley 6221/2182A current source/nanovoltmeter assembly. The gate potential is controlled through a Keithley 2410 sourcemeter, whose negative electrode is set at the current drain contact. Gate leakage is monitored to ensure that no electrochemical reactions occur at the graphene/EDL interface. Magnetoresistance measurements are performed in an Oxford Instruments helium cryostat equipped with a superconducting magnet.

We estimate $n_{2d}$ as a function of the gate voltage, $V_G$, from the measured gate current through double-step chronocoulometry [39] (DSCC), as shown in figure 1(c) for 3LG, 4LG and 5LG (green triangles, violet diamonds and orange pentagons, respectively) and described in detail in ref. [23]. This technique is based on the fact that, in absence of chemical reactions at the electrodes, the current flowing through the electrolyte can be split into two contributions [39]. The first, due to the EDL build-up, decays exponentially over time [39]. The second, due to ion diffusion through the bulk of the electrolyte [39], decays as the square root of time [39]. By fitting the gate current response to a step-like application and removal of $V_G$ with a function that separately accounts for both effects, the two contributions can be distinguished and, thus, the EDL charge estimated. Further details on the technique can be found in refs. [21, 23, 39]. These results are checked with independent Hall-effect measurements performed on a 4LG device (red squares in figure 1(c)). We conservatively use the DSCC values in the full $V_G$ range.

We also compare the RT resistance as a function of $V_G$ in a 3LG with the earlier measurements of ref. [17]. Figure 1(d) shows how, in both cases, regions of sharp non-monotonic behavior are present in the resistance curves away from the Dirac point. The position of these upturns is associated with a specific charge density, such that the Fermi level, $E_F$, is crossing the bottom of the split-off bands [17], which can be used for voltage-$n_{2d}$ calibration. This comparison indicates that our PES allows us to reach the split-off bands at lower potential than the ionic liquid of ref. [17], thus supporting a higher charge induction capability.

### 3. Results and discussion

We first measure the four-contact resistance in the 4–290 K range as a function of $N$ and $n_{2d}$. In each measurement, $V_G$ is applied at RT and the system
is then cooled to a base temperature $T \sim 4\text{–}10\text{ K}$, depending on the sample. Any further modification of $n_{2d}$ below the PES glass transition at $\sim 230\text{ K}$ [23] is prevented by the quenched ion motion [4, 6]. The samples are then allowed to spontaneously warm up, taking advantage of the absence of $T$ fluctuations associated with the cryocooler’s thermal cycles. We reported a detailed analysis of the $T$ dependence of $R_S$ for these devices in the $30\text{–}290\text{ K}$ range in ref. [23]. Here we focus on the anomalous behavior that emerges in the $4\text{–}30\text{ K}$ range.

For all the three $N$, a logarithmic upturn is observed for $T < 100\text{ K}$ in the resistance curves for samples in the metallic regime, as shown in figure 2. Figures 2(a)–(d) plot the low-$T$ variations of $R_S$ with respect to its minimum value $R_{\text{SMin}}$ for 3LG, 4LG and 5LG as function of $T$ in a semi-logarithmic scale. $R_{\text{SMin}}$ decreases with increasing $n_{2d}$ for all $N$, and saturates for 4LG (see top panel of figure 2(e)). Both the amplitude of the logarithmic upturn ($R_S(5\text{ K}) - R_{\text{SMin}}$) and the $T_{\text{Min}}$ at which $R_{\text{SMin}}$ is reached strongly depend on $n_{2d}$ and $N$, as shown in the central and bottom panels of figure 2(e). Similar logarithmic upturns in the resistances of conductors in the diffusive regime, such as Si MOSFETs [41], GaAs heterostructures [42, 43], and transition metal alloys [44] are usually attributed to Kondo effect [45], WL [46, 47], and $e-e$ interactions [50–52], or to a superposition of any of the previous sources [49].

We first consider the Kondo effect, which is caused by carrier scattering from diluted magnetic impurities [44, 45]. Unlike in ref. [48], we do not intentionally introduce any defects in our samples. We thus employ Raman spectroscopy to monitor the amount of Raman active defects in our devices, before and after PES drop-casting. Raman measurements are carried out at RT in a Renishaw InVia microspectrometer equipped with a 100X objective. The spot size is $\sim 1\mu m$, the excitation wavelength is 514 nm and the incident power is kept well below 1 mW in order to avoid heating. Figure 3(a) plots the Raman spectrum of a 3LG device. The PES shows several peaks between $\sim 1000$ and $1500\text{ cm}^{-1}$. The broad peak between $\sim 1400$ and $1500\text{ cm}^{-1}$ can be assigned to the methylene bending mode [102], the peak at $\sim 1280\text{ cm}^{-1}$ to methylene twisting [103], and that at $\sim 1243\text{ cm}^{-1}$ to either trifluoromethyl stretching [102] or methylene twisting [103].

We perform a background subtraction by normalizing to the low-frequency PES peaks near the D peak. This gives an upper limit for the ratio between the intensity of the D peak and the intensity of the G peak, $I(D)/I(G)$, $\sim 0.015$, which leads to an estimated defect density $\sim 3 \times 10^{9} \text{ cm}^{-2}$ [37, 38]. For comparison, in order to obtain a sizeable Kondo effect (Kondo temperature $\delta \rho/\rho \approx 6\%$ at $T = 0.3\text{ K}$), in ref. [48] it was necessary to induce a defect density $\sim 3 \times 10^{11} \text{ cm}^{-2}$, which produced a corresponding $I(D)/I(G) \sim 2.8$, for an excitation wavelength of $633\text{ nm}$ [48]. Our values indicate that our devices are at least two orders of magnitude less defective. Thus, we discard contributions from the Kondo effect to the resistance upturn.

3.1. Weak localization in few-layer Graphene

WL arises from the constructive interference between pairs of time-reversed trajectories of electrons...
elastically scattering in a closed loop [49]. This increases the probability of charge-carrier backscattering in a conductor in the diffusive regime [46, 47], thus reducing the conductance [49]. In order for WL to appear, phase coherence must be maintained throughout the entire closed loop, followed by the electrons undergoing elastic scattering, as described by a characteristic lifetime $\tau_e$ [46]. WL is thus suppressed by an increased probability of inelastic scattering associated with the $T$ increase [46]. The average time interval in which phase coherence is maintained is called phase coherence lifetime $\tau_\phi$ [49]. Typically, two inelastic processes determine $\tau_\phi$ [49]. E–ph scattering [53], which is important for higher $T$ [49], and e–e scattering [54, 55], which dominates for lower $T$ [49]. The $T$ that marks a crossover between these two scattering processes depends on the transport properties of each material [49], and it is typically of the order of few tens K [49].

In a diffusive system a conductivity suppression at low $T$ may also be caused by e–e interactions, as a result of the diffraction of an electron wave by the oscillations in the electrostatic potential generated by the other electrons [49–52]. A widely exploited approach to discriminate between these two contributions is the measurement of the sample magnetoconductance [49, 50, 56]. In the presence of a perpendicular magnetic field $B$, time-reversal symmetry is broken [49]. A phase difference arises between any two time-reversed electron trajectories, whose constructive interference, in principle able to localize electrons [49], is therefore broken [56]. As a consequence [49]: (i) a negative magnetoconductance is associated with WAL [57]; (ii) a vanishing magnetoconductance is associated with e–e interaction (insensitive to $B$) [56]; (iii) a positive magnetoconductance is associated with WL [56, 57].

In order to determine the origin of the resistance upturn we thus measure the magnetoconductance of a 3LG device at 2 K. We find it positive, and reaching a maximum at $B_x = 2h/4e\tau_\phi^2\tau^2$ = 0.021 T, as shown in figure 4(a), where the magnetoconductance relative to the value at zero field is plotted as a function of $B$. In order to rule out even a partial contribution from e–e interactions, we also measure the device resistance while heating the sample under $B = B_x$. Figure 4(b) shows that the logarithmic upturn is suppressed within the noise level. This behavior is reversible upon removal of $B$. The logarithmic upturn saturates for $T \lesssim 4$ K, a feature usually assigned to the effect of finite channel size [66]. These data support the conclusion that, in our devices, WL is the source of the measured resistance upturn and that the logarithmic correction to the conductivity due to e–e interaction can be disregarded. This is in contrast with earlier reports on SLG, where both contributions were shown to be relevant [69]. We also note that the magnetoconductance behavior of our 3LG is qualitatively different from that in ref. [18], where spin–orbit coupling was found to affect the magnetoconductance behavior of EDL-gated 3LG. We do not observe any significant influence of spin–orbit coupling. We note, however, that the devices reported in ref. [18] were obtained from FLG grown on silicon carbide. The enhanced spin–orbit coupling reported in ref. [18] may thus be associated both with the different fabrication process and substrate.

The carrier lifetimes determine the WL behavior [49, 57], and can thus be obtained from figure 4(a) [58, 59]. In SLG it was predicted that, due to lattice symmetries, an additional $\pi$ Berry phase is accumulated by charge carriers scattering in closed loops [62–64]. In 2LG such additional Berry phase is instead $2\pi$ [59, 65]. This means that in SLG the quantum interference due to localization is always destructive [60, 61], leading to an anti-localization [57], while in 2LG the effect of the additional phase cancels out, and the material should retain the standard WL behavior [59]. In addition, WAL, where the underlying elastic scattering mechanism is due to charged impurities, is strongly suppressed by intervalley scattering and trigonal warping [58]. Furthermore, refs. [58, 59] showed that SLG and 2LG have another quantum correction to the Drude resistivity, always localized, due to elastic intervalley scattering, and not affected by trigonal warping. As a consequence, various localization behaviors were reported [57, 66, 67, 81–85], depending on the sample preparation and on the explored regime.

To the best of our knowledge, a WL model for $N > 2$ has not yet been developed. Earlier WL reports in FLG made use of models developed for SLG and 2LG [89–91].
The simultaneous presence of both Dirac-like and parabolic bands in odd-N flakes [92, 93] makes an \textit{a priori} determination of the total Berry phase difficult. The correction to the conductance due to the Berry phase is suppressed in all our experiments. This allows us to conclude that only elastic intervalley scattering is relevant for quantum interference.

Following the theoretical approach of ref. [59], the $T$ dependence of the quantum correction to the 2D conductance is determined by the $T$ behavior of the phase coherence lifetime $\tau_p$, as:

$$\delta\sigma_{\text{WL}}(T) = \frac{e^2}{\pi h} \ln \left[ 1 + 2 \frac{\tau_p(T)}{\tau_i} \right] - \delta_0(\tau_p, \tau_0, \tau)$$

(1)

where $\tau_i$ is the intervalley scattering lifetime, $\tau_p = 2\tau_i$ is the transport lifetime (associated with scattering from charged impurities [66, 67]) and $\tau$ is an effective lifetime associated with intravalley scattering and trigonal warping. On the right hand side of equation (1), the first term arises from intervalley scattering, and resembles the conventional WL correction [49], apart from the factor two and the different elastic lifetime involved. Since the argument of the logarithm is always greater than one, this term is always negative. The second term, arising from intravalley scattering, is positive or negative depending on the Berry phase, and always greater than one, this term is always negative. This approach is sound, since the smallest doping in our measurements is $\sim 1 \cdot 10^{13}$ cm$^{-2}$, a large value for solid-dielectric gating experiments [7, 8], and we do not find anti-localized behavior at these doping levels. Refs. [66, 67, 80] also reported that doping strongly enhances $\tau_p^{-1}$ (thus reducing $\delta_0$), since trigonal warping becomes more relevant the higher the energy separation from the Dirac point. This makes our approximation $\delta_0 = 0$ valid also for higher doping.

We can thus write the complete expression for the conductance of our FLG devices, valid for $T \lesssim 90\, \text{K}$:

$$\sigma_{\text{2d}} = \sigma_{\text{Drude}} + \delta\sigma_{\text{WL}}$$

(3)

where $\sigma_{\text{Drude}}$ is [71]:

$$\sigma_{\text{Drude}} = \frac{e^2}{4} \tau \sum_i (\nu_i \nu_i' \nu_i'' N_i) = e^2 \tau P(n_{\text{2d}})$$

(4)

Here $\nu_i$, $\nu_i'$, and $\nu_i''$ are the valley and spin degeneracies, respectively, $\nu_0$ is the Fermi velocity and $N_i$ is the DOS at the $E_F$ of the $i$th band. Taking into account the Matthiessen rule [101] on the carrier lifetime at finite $T$ we have:

$$\tau^{-1} = \tau_{\text{tr}}^{-1} + \tau_{\text{inel}}^{-1}$$

(5)

where $\tau_{\text{inel}}$ is the $T$-dependent inelastic scattering lifetime. Substituting in equation (3) we get:

$$\sigma_{\text{2d}} = e^2 P(n_{\text{2d}}) \cdot \left( \tau_{\text{tr}}^{-1} + \tau_{\text{inel}}^{-1} \right)^{-1} = \frac{e^2}{\pi h} \ln \left( 1 + 2 \frac{\tau_p}{\tau_i} \right)$$

(6)

In order to proceed further, we need to determine the prefactor $P(n_{\text{2d}})$, the transport lifetime $\tau_{\text{tr}}$ and the $T$ dependence of $\tau_p$.

We estimate $P(n_{\text{2d}})$ by computing the FLG bandstructure through \textit{ab initio} Density Functional Theory (DFT) for all our doping levels. We also perform a consistency check of the DFT estimations by running independent self-consistent tight-binding calculations for the doped 4LG. Here we present the results for Berrial stacked 4LG and 5LG. As a first approximation, we assume these systems to be isolated, i.e. we consider the effects of the substrate to be negligible.

We first investigate the band-structures of FLG within the all-electron, full-potential, linear augmented plane wave (FP-LAPW) method as implemented in the ELK code [72]. The local density approximation (LDA)
is known, the convergence is checked for 4LG by comparing DFT with tight-binding (see figures 6(a) and (b)). Since, for $T \lesssim 30$ K, we can assume almost independent of $T$ [66], the T dependence of $\tau_\phi$ is the same as that of $\tau_\psi$. By expressing $\tau_\psi \approx T^{-\beta}$, we associate the parameter $\beta$ to specific scattering processes. For $T$ lower than the Bloch–Gruneisen $T$ [19], e–ph scattering gives $p = 3$ for a standard 2-dimensional electron gas (2DEG) [53] and $p = 4$ for SLG [19]. The e–e scattering is thus the dominant mechanism in this $T$ range. This is consistent with the existing literature on SLG [66] and 2LG [68, 70]. In ref. [23] we reported that the $T$ dependence below 100 K has a linear plus a quadratic contribution, the linear being dominant for $T_{\text{bulk}} \lesssim T \lesssim 30$ K (see figures 4(a) and 5(c) of ref. [23]) and assigned this to competing Coulomb and Nyquist e–e scattering processes. This is consistent with the present observation of a dominant Nyquist contribution for $T < 20$ K.

As any energy exchange with the surrounding environment breaks phase coherence [49], WL is suppressed by an increased probability of inelastic scattering associated with the $T$ increase [46]. Thus, since the most relevant contribution to the phase-breaking time $\tau_\psi$ arises from the inelastic scattering due to e–e interaction $\tau_{\text{inel}} e e$ [49], we can write the $T$ dependence of $\tau_\psi$ in the entire 4–90 K range as:

$$\tau_\psi^{-1} \approx \tau_{\text{inel}}^{-1} = A \cdot T + B \cdot T^2$$  (8)

By inserting equation (8) in the first terms of the Drude conductance of equation (6), we can fit the curves at different doping in the intermediate $T$ region (30–90 K) where the WL contribution can be neglected. With the previously determined values of $P(n_{\text{dal}})$ and $\tau_{\text{inel}}(n_{\text{dal}})$, this fit provides us the parameters $A(n_{\text{dal}})$ and $B(n_{\text{dal}})$. Finally, combining $\tau_{\text{inel}}(T)$ determined here with $\tau_\phi(T)/\tau_\psi$ obtained from the low $T$ (4–20 K) region, we can extract $\tau_\psi(n_{\text{dal}})$. Figure 6(b) shows the agreement between a fit based on equation (8) (black dashed lines) and the experimental data in the WL region (solid lines).

We first apply this procedure to the $R_S$ as a function of $T$ curves of the device on which the magnetoresistance was measured, obtaining $\tau_\psi = 39.7$ ps and...
\( \tau_i = 49.7 \) ps at 4 K, in agreement with the values coming from the magnetoresistance fit at 2 K. Once again, the comparison is carried out at 4 instead of 2 K due to the signal saturation for \( T \leq 4 \) K in figure 4(b). This comparison indicates that the analysis of the magnetococonductance and of the \( T \)-dependence of \( R_S \) leads to equivalent estimates for \( \tau_{\phi} \) and \( \tau_i \). Thus, since we can perform the \( R_S \) versus \( T \) characterization of our devices more easily and more extensively than the magnetotransport measurements, due to the thermal expansion coefficient mismatch between the devices and the frozen electrolyte, we repeat the \( R_S \) versus \( T \) analysis on the 4LG and 5LG devices for different \( V_G \).

3.3. Transport scattering lifetime versus carrier density

We now discuss the measured trends of \( \tau_t \) as a function of \( n_{2d} \). In standard 2DEGs, such as GaAs heterostructures [43], \( \tau_t \) is equivalent to the elastic scattering lifetime (\( \tau_{el} = \tau_t \)) and follows a \( n_{2d} \) dependence, \( 1 < \gamma < 2 \) [43, 94, 95]. This implies that \( \tau_t \) increases for increasing \( n_{2d} \) due to the increased
screening of elastic scatterers by the increased density of charge carriers [86, 87]. In our devices, however, $\tau_\infty$ does not follow this behavior, suggesting a significant increase of the number of elastic scatterers with increasing gate voltage.

If we consider the 4LG device first, we observe that $\tau_\infty$ shows a monotonically decreasing behavior (figure 7(a), blue dots). One possible explanation was suggested in ref. [88], where the authors reported a decreasing mobility at high $n_{2d}$ for 2DEGs. In contrast to Coulomb disorder, short-range disorder would become stronger with increasing $n_{2d}$, thus increasing the scattering rate [88]. However, we think that this is not the main source of the increase of $\tau_\infty$ in our case. A degradation of the mobility of EDL-gated devices was reported in strontium titanate [76] and rhenium disulfide [77], where it was suggested that ions in the electrolyte act as charged impurities. Thus, we attribute this effect to the microscopic dynamics of how EDL gating induces extra carriers. EDL gating is able to induce modulations in excess of $10^{14} \text{cm}^{-2}$ to $n_{2d}$ by accumulating a packed layer of ions in close proximity ($\sim$1 nm [7, 8]) to its surface. Refs. [78, 79] reported that charge-donating impurities at the SLG surface act as scattering centers.

We thus propose that the Li$^+$ ions in the EDL have a similar role. Their increased density with $V_G$ competes with the increased screening induced by the extra carriers and this determines $\tau_\infty$. In 4LG, the former effect would be stronger in the entire $n_{2d}$ range, resulting in the monotonic reduction of $\tau_\infty$. If this is the case, we expect 5LG to be less sensitive to the extra scattering centers. These are localized at the surface of the first layer, and ref. [76] showed that introducing a thin spacer between the ions and the conductive channel greatly improves carrier mobility. With respect to 4LG, 5LG features one further conductive channel due to the fifth layer, which is thus further separated from the scattering centers. Indeed, this is what we observe: the 5LG device shows an initial decrease for $n_{2d} \lesssim 2 \cdot 10^{14} \text{cm}^{-2}$ followed by an increase for $n_{2d} \gtrsim 4 \cdot 10^{14} \text{cm}^{-2}$ (figure 7(b), blue dots). Overall, the $\tau_\infty$ in 5LG is nearly constant with $n_{2d}$, as if the two competing effects on mobility were almost canceling out. As for 3LG, we estimate $\tau_\infty \sim 2.5$ fs at $n_{2d} \sim 5.2 \cdot 10^{14} \text{cm}^{-2}$, which is smaller than in 4LG. This corresponds to a suppression by a factor $\sim$18 of the low-$n_{2d}$ value in 3LG, higher than the $\sim$15 times one in 4LG. Thus, 3LG appears even more sensitive to the accumulation of scattering centers at its surface than 4LG, in accordance with the previous results.

3.4. Dephasing and intervalley scattering lifetimes versus carrier density

Let us now consider the doping dependence of $\tau_\infty$ and $\tau_\infty$ in 4LG and 5LG, in order to allow for a direct comparison with the corresponding values for 3LG estimated from magnetoresistance. Figure 7 shows that the doping dependence of $\tau_\infty$ is weakly decreasing or nearly constant within the uncertainty range: from 6.6 $\pm$ 0.7 ps to 1.7 $\pm$ 0.9 ps for 4LG, from 9.8 $\pm$ 4.1 ps to 7.6 $\pm$ 5.0 ps for

![Figure 6](image-url)

**Figure 6.** (a) $\tau_{\phi}/\tau_\infty$ as a function of $1/T$ obtained from the low-$T$ data ($4 < T < 20$ K) of figure 2(a) (4LG); (b) The same as in (a) but for the low-$T$ data of figure 2(d) (5LG). Dashed lines are fits to the experiments according to equation (8). Best fits for 4LG are omitted for clarity.

![Figure 7](image-url)

**Figure 7.** (a) $n_{2d}$ dependence of $\tau_\infty$ (black dots), $\tau_\infty$ (red dots), $\tau_\infty$ (blue dots) and $\tau_\infty$ (orange dots and shaded band) at 4 K in 4LG; (d) The same as in (a) but for 5LG. Dashed lines act as guides to the eye.
5LG. This dependence was already observed [66, 80], albeit for \( n_{2d} \lesssim 1.5 \times 10^{13} \, \text{cm}^{-2} \), much lower than the \( n_{2d} \) considered here (\( n_{2d} \gtrsim 1 \times 10^{14} \, \text{cm}^{-2} \)). In contrast, the doping dependence of \( \tau_\varphi \) is more significant, as it is monotonically decreasing in the entire range in 4LG, while it shows a small inversion in slope on the final point for 5LG. These results are in contrast with earlier findings on FLG for \( n_{2d} < 2 \times 10^{13} \, \text{cm}^{-2} \) [80]. As already pointed out, e–e Nyquist scattering is the dominant dephasing mechanism in the low \( T \) range. Therefore, we can write [43]:

\[
\tau^{-1}_{\varphi \text{e–e}}(T) = \frac{k_B T \ln(x)}{2 \hbar}, \quad x = \frac{E_F \tau_\varphi}{\hbar}.
\] (9)

The condition \( x \sim 1 \) (Ioffe–Regel criterion [96]) characterizes the Anderson metal-to-insulator transition [97]. The metallic regime corresponds to \( x \gg 1 \), leading to a \( \tau_\varphi \) increasing with \( n_{2d} \) (i.e. with increasing \( E_F \)). Under strong localization conditions, \( x < 1 \) and the Boltzmann model no longer holds [98]. Intermediate values of \( x \) mark a crossover from strong to weak localization [99] and correspond to a region where \( \tau_\varphi \) can exhibit a decreasing behavior with \( n_{2d} \). The exact form of the \( \tau_\varphi \) curve is determined by the dependence of \( E_F \) on \( n_{2d} \), which, in the linear region of the bands, is a square root [100] and on \( \tau_\varphi \). If we compute the value of \( x \) corresponding to our data by using the \( \tau_\varphi \) determined at 4 K, we find that, for 4LG, \( x = 2.7 \pm 0.2 \) in the entire range of negative charge induction, while, for 5LG, \( x < 2.7 \) for \( V_G = 1 \) and \( 2 V \), \( x > 5 \) for \( V_G = 3 \) and \( 4 V \). Thus, the 4LG device is always in the ‘crossover’ condition, while in 5LG the typical 2DEG behavior is restored for \( n_{2d} \gtrsim 2 \times 10^{14} \, \text{cm}^{-2} \). Due to the dependence of \( x \) on \( \tau_\varphi \), these results are consistent with the fact that the ion dynamics in the EDL gating provides a competition between an increase in the number of elastic scattering centers and of \( n_{2d} \) with increasing \( V_G \). In 4LG the concurrent increase of \( E_F \) and decrease of \( \tau_\varphi \) (see figure 7(a)) could maintain \( x \) almost constant. In 5LG at \( n_{2d} \gtrsim 2 \times 10^{14} \, \text{cm}^{-2} \) the increase of both \( E_F \) and \( \tau_\varphi \) (see figure 7(b)) would eventually lead to the increase of \( x \). This behavior could be due to the differences in both surface-to-volume ratio and bandstructure of 4LG and 5LG, and is in agreement with the behavior of \( \tau_\varphi \) in the two samples.

3.5. Comparison with the single-band scattering model

In order to further analyze these results, we evaluate the theoretical values of the e–e scattering lifetimes by using the definition of \( x \) given in equation (9) with \( E_F(n_{2d}) \) determined by DFT and \( \tau_\varphi \) taken from the determined \( \tau_\varphi \) values. The results are shown in figure 7 as orange circles and shaded bands (that represent the uncertainty regions). Our \( \tau_\varphi \) (black dots) are in agreement with the theoretical predictions within an order-of-magnitude. However, the latter are nearly doping-independent in contrast with experiments. This different behavior is particularly evident in 4LG. As expected, the addition of the Coulomb scattering term [66] does not affect appreciably the predicted values at this low \( T \). Since the theoretical \( \tau_\varphi \) are dependent on the details of the \textit{ab initio} calculations, the inconsistency might be related to the approximations in the DFT calculations of the effects of the high electric field. However, a more important reason for the mismatch lies in the limitation of the hypotheses underlying the theoretical derivation of the Nyquist scattering. Both the single-band and the parabolic-dispersion assumptions do not hold in FLG, particularly when the \( E_F \) is so far from the Dirac point [92, 93].

3.6. Comparison with the scattering lifetimes as determined by pump-probe spectroscopy

A comparison with the other experimental technique able to probe the e–e scattering lifetime, i.e. pump-probe spectroscopy, is not immediate, due to the different conditions in the probed electron system between transport and spectroscopic measurements. Low-bias (<0.2 V [105]) transport measurements, such as the ones in this work, involve only scattering processes between carriers very close to the \( E_F \). Pump-probe measurements, on the other hand, generate a strongly out-of-equilibrium carrier population by optical excitation. This population first thermalizes to a quasi-equilibrium distribution of ‘hot’ carriers via e–e [106, 108, 111] and e–ph [105–110] scattering processes. The ‘hot’ carriers then cool down to the rest of the Fermi sea over a much longer time scale by scattering with optical phonons [105–111]. This makes the two types of measurements hardly comparable, as the e–e scattering lifetime is heavily dependent on the difference in energy between the scattering electrons and the \( E_F \) [104, 112]. Moreover, pump-probe experiments are typically performed at room \( T \) [106–108, 110, 111], where the Coulomb term dominates e–e scattering, while our experiments are at low \( T \), where the Nyquist term dominates. With all these caveats, if we extrapolate to room \( T \) the e–e scattering lifetimes using equation (9) and imposing \( T = 300 \, \text{K} \). This gives \( \tau_{\varphi \text{e–e}} \) between \( \sim 1 \) and \( 7 \) fs, in agreement with existing literature [106, 108, 111].

4. Conclusions

We explored the electronic transport properties of 3-, 4- and 5-layer graphene in the doping regime in excess of \( \sim 10^{13}–10^{14} \, \text{cm}^{-2} \) and in the 4–30 K temperature range. We used electric double layer gating to dope the samples up to \( \sim 7 \times 10^{14} \, \text{cm}^{-2} \). We found evidence of quantum coherent transport in the entire carrier density range. Magnetoreistance measurements showed that, in the 4–30 K range, transport is dominated by weak localization in the diffusive regime, and that the behavior of 3LG, 4LG and 5LG is described by the theoretical models developed for SLG and 2LG. We combined the experimental results with DFT calculations to determine the carrier scattering lifetimes as a function of the carrier density for different number of layers, and determined
that electron–electron scattering with small momentum transfer (Nyquist process) is the main source of dephasing at low temperatures. Both the transport scattering lifetime and the phase coherence lifetime show a non-trivial dependence on $\tau_{\phi}$. We explained the behavior of $\tau_{\phi}$ in terms of a competing modulation of doping and density of charged scattering centers induced by EDL gating. The doping dependence of $\tau_{\phi}$ points to a gate-tunable crossover from weak to strong localization, highlighting the limits of applying single-band models to multi-band systems, such as heavily doped few-layer graphene.

Acknowledgments

We thank M Calandra, M Polini and V Brosco for useful discussions. We acknowledge funding from EU Graphene Flagship, ERC Grant Hetero2D, EPSRC Grant Nos. EP/ K01711X/1, EP/K017144/1, EP/N010345/1, and EP/L016087/1 and the Joint Project for the Internationalization of Research 2015 launched by Politecnico di Torino under funding of Compagnia di San Paolo.

References

[38] Cancado L, Get al 2011 Quantifying defects in graphene via Raman spectroscopy at different excitation energies Nano Lett. 11 3190
[53] Taboryski R and Lindelhof P E 1990 Weak localization and electron–electron interactions in modulation-doped GaAs/AlGaAs heterostructures Semicond. Sci. Technol. 5 533
[63] Suzuura H and Ando T 2002 Crossover from symplectic to orthogonal class in a two-dimensional honeycomb lattice Phys. Rev. Lett. 89 266603
[65] Novoselov K S 2006 Unconventional quantum Hall effect and Berry’s phase of $\mathcal{Z}_2$ in bilayer graphene Nat. Phys. 2 177
[77] Ovchinnikov D, Gargiulo F, Allain A, Pasquier D J, Dumencu D, Ho C H, Yazey O V and Kis A 2016 Disorder engineering and conductivity dome in ReS 2, with electrolyte gating Nat. Commun. 7 12391
[82] Berger C et al 2006 Electronic confinement and coherence in patterned epitaxial graphene Science 312 1191
[96] Ioffe A. F and Regel A R 1960 Non-crystalline, amorphous and liquid electronic semiconductors Prog. Semicond. 4 237
[104] Li Q and Das Sarma S 2013 Finite temperature inelastic mean free path and quasiparticle lifetime in graphene Phys. Rev. B 87 085406